

## Deutsche Akkreditierungsstelle GmbH

**Entrusted according to Section 8 subsection 1 AkkStelleG in connection with Section 1 subsection 1 AkkStelleGBV**

Signatory to the Multilateral Agreements of EA, ILAC and IAF for Mutual Recognition

# Accreditation



The Deutsche Akkreditierungsstelle GmbH attests that the testing laboratory

**TASCON Gesellschaft für Oberflächen- und Materialcharakterisierung mbH**

for its locations

**Mendelstraße 17, 48149 Münster**  
**Otto-Volger-Straße 19, 65843 Sulzbach/Ts.**

is competent under the terms of DIN EN ISO/IEC 17025:2005 to carry out tests in the following fields:

**Physical-chemical analysis of the chemical, elemental and molecular composition of surfaces, interfaces, near-surface layers, complex layer systems, trace impurities and near-surface volume material including the lateral and depth distribution on solids, cross sections, powders, particles, fibres, liquids, and paints by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS) and X-Ray Photoelectron Spectroscopy (XPS / ESCA); determination of the roughness of surfaces by means of Optical Profilometry**

The accreditation certificate shall only apply in connection with the notice of accreditation of 24.05.2017 with the accreditation number D-PL-17283-01 and is valid until 23.05.2022. It comprises the cover sheet, the reverse side of the cover sheet and the following annex with a total of 3 pages.

Registration number of the certificate: **D-PL-17283-01-00**

Berlin,  
24.05.2017

Dipl.-Ing. (FH) Ralf Egnér  
Head of Division

Translation issued:  
10.10.2019

  
Head of Division

# Deutsche Akkreditierungsstelle GmbH

Office Berlin  
Spittelmarkt 10  
10117 Berlin

Office Frankfurt am Main  
Europa-Allee 52  
60327 Frankfurt am Main

Office Braunschweig  
Bundesallee 100  
38116 Braunschweig

The publication of extracts of the accreditation certificate is subject to the **prior written approval** by Deutsche Akkreditierungsstelle GmbH (DAkKS). Exempted is the **unchanged form of separate disseminations** of the cover sheet by the conformity assessment **body mentioned overleaf**.

No impression shall be made that the accreditation also extends to fields beyond the scope of accreditation attested by DAkKS.

The accreditation was granted pursuant to the Act on the Accreditation Body (AkkStelleG) of 31 July 2009 (Federal Law Gazette I p. 2625) and the Regulation (EC) No 765/2008 of the European Parliament and of the Council of 9 July 2008 setting out the requirements for accreditation and market surveillance relating to the marketing of products (Official Journal of the European Union L 218 of 9 July 2008, p. 30). DAkKS is a signatory to the Multilateral Agreements for Mutual Recognition of the European co-operation for Accreditation (EA), International Accreditation Forum (IAF) and International Laboratory Accreditation Cooperation (ILAC). The signatories to these agreements recognise each other's accreditations.

The up-to-date state of membership can be retrieved from the following websites:

EA: [www.european-accreditation.org](http://www.european-accreditation.org)

ILAC: [www.ilac.org](http://www.ilac.org)

IAF: [www.iaf.nu](http://www.iaf.nu)

Deutsche Akkreditierungsstelle GmbH

## Annex to the Accreditation Certificate D-PL-17283-01-00 according to DIN EN ISO/IEC 17025:2005

Period of validity: 24.05.2017 to 23.05.2022 Date of issue: 10.10.2019

Holder of certificate:

**TASCON Gesellschaft für Oberflächen- und Materialcharakterisierung mbH**

for its locations

**Mendelstraße 17, 48149 Münster**  
**Otto-Volger-Straße 19, 65843 Sulzbach/Ts.**

Tests in the fields:

**Physical-chemical analysis of the chemical, elemental and molecular composition of surfaces, interfaces, near-surface layers, complex layer systems, trace impurities and near-surface volume material including the lateral and depth distribution on solids, cross sections, powders, particles, fibres, liquids, and paints by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS) and X-Ray Photoelectron Spectroscopy (XPS / ESCA); determination of the roughness of surfaces by means of Optical Profilometry**

Abbreviations used: see last page

**Within the given testing field marked with \* the testing laboratory is permitted, without being required to inform and obtain prior approval from DAkkS, the modification, development and refinement of testing methods. The listed testing methods are exemplary.**

**The laboratory maintains a current list of all standards / testing procedures within the flexible scope of accreditation.**

**Within the scope of accreditation marked with \*\*, the testing laboratory is permitted, without being required to inform and obtain prior approval from DAkkS, to use standards or equivalent testing methods listed here with different issue dates.**

Test procedures are marked with the following symbols for the locations at which these are in use:

MS = Münster

MTK = Sulzbach/Ts.

**1 Determination of the chemical, elemental and molecular composition of surfaces, interfaces, near-surface layers, complex layer systems, trace impurities, and near-surface volume material including the lateral and depth distribution on solids, cross sections, powders, particles, fibres, liquids, and paints by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS) \***

VA-P03-100-Spektren- akquisition / 3 2017-02	Chemical characterisation of surfaces by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS): Spectrometry	MS
VA-P03-110-Image- akquisition / 3 2017-02	Chemical characterisation of surfaces by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS): Imaging	MS
VA-P03-120-Tiefenprofil- akquisition / 2 2017-02	Chemical characterisation of surfaces by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS): Depth Profiling	MS
VA-P03-140-Quantifizierung- von-B-in-Si / 2 2017-02	Quantitative Detection of Boron in Silicon (ToF-SIMS)	MS

**2 Determination of the chemical, elemental and molecular composition of surfaces, interfaces, near-surface layers, complex layer systems, trace impurities, and near-surface volume material including the lateral and depth distribution on solids, cross sections, powders, particles, fibres, liquids, and paints by means of X-Ray Photoelectron Spectroscopy (XPS / ESCA) \***

VA-P03-210-XPS-Messen- und-Auswerten_Spektros- kopie / 0 2017-02	XPS/ESCA measurement and data evaluation: Spectroscopy	MTK
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**Annex to the accreditation certificate D-PL-17283-01-00**

VA-P03-230-XPS-Messen- und-Auswerten_Imaging / 0 2017-02	XPS-/ESCA- measurement and data evaluation: Imaging	MTK
VA-P03-230-XPS-Messen- und-Auswerten_Imaging / 0 2017-02	XPS-/ESCA- measurement and data evaluation: Imaging	MTK
VA-P03-240-XPS-Messen- und-Auswerten_Tiefen- profilierung / 0 2017-02	XPS-/ESCA-measurement and data evaluation: Depth profiling	MTK

**3 Determination of the roughness of surfaces by means of Optical Profilometry \*\***

DIN EN ISO 4287 2010-07	Geometrical Product Specifications (GPS) - Surface texture: Profile method - Terms, definitions and surface texture parameters	MS
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**Abbreviations used:**

VA-P...	Operation procedure of internal procedures and methods of Tascon GmbH
XPS	X-ray Photoelectron Spectroscopy
ESCA	Electron Spectroscopy for Chemical Analyses